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High Perfomance and all-round TOFMS

AccuTOF GCX

▶ High performance

Reliable determination of elemental composition

The high-resolution and high mass accuracy AccuTOF GCx enables accurate elemental composition determination, which is a powerful tool for the qualitative analysis of unknown compounds and impurities.

High-speed data acquisition

The AccuTOF GCx performs high throughput analysis using Fast GC with its high-speed data acquisition capability (50 spectra/s). It also supports GCxGC for ultrahigh separation analysis.

▶ All-round

A variety of ionization and sample introduction techniques

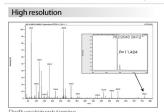
While electron ionization (EI) is effective in acquiring structural information, detection of molecular ions is critical in qualitative analysis of unknown compounds.

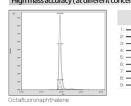
In addition to chemical ionization (CI), the AccuTOF GCx supports field ionization (FI) and field desorption (FD), which are powerful soft ionization techniques for molecular ion detection.

The system also supports direct sample inlets for analysis of high boiling point compounds and rapid



■ Elemental composition determination by accurate mass analysis



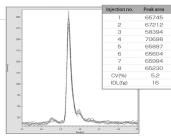


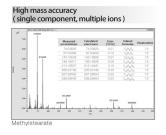
■ High sensitivity

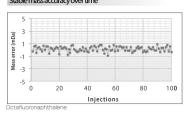
100fg CV=5.2%, IDL=16fg

 $\label{light} \textbf{High mass accuracy (at different concentrations, single ion)} \ \ 100\,fg \ of \ octafluor \ on a phthalene (OFN) \ was \ measured$ continuously 8 times. From the standard deviation of the EIC peak areas of OFN molecular ions, an instrument detection limit (IDL) of 16 fg was calculated. CV: Coefficient of variation

IDL: Instrument detection limit

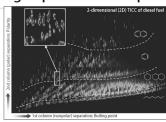




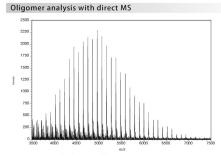


■GCxGC analysis by ultrahigh speed data acquisition

Accurate mass measurements are easily accomplished in GCxGC analysis, which requires ultrahigh speed data acquisition. This is especially effective for nontargeted qualitative analysis of trace components.



■ Wide mass range

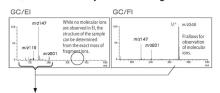


The AccuTOF GCx, with a wide mass range and direct inlet system, can analyze samples with large molecular weights that are difficult to handle with GC.

EI/FI/FD combination ion source (optional)

JEOL's unique ion source combining El, Fl, and FD ionization allows for GC/El, GC/Fl, and FD analysis without changing the ion source. The single ion source supports highly productive analysis without breaking the vacuum.

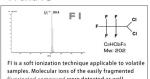
· Qualitative analysis combining EI and FI





The El mass spectrum allows for library search. The elemental composition of fragment ions results in structural information. Meanwhile, molecular ions detected in FI suggest the molecular weight and elemental composition. By combining the information resulting from EI and FI, one can achieve highly accurate qualitative analysis without relying solely on library search. The combined technique is effective in qualitative analysis of unknown components such as impurities.

FI and FD





acquired from nonvolatile ionic liqui

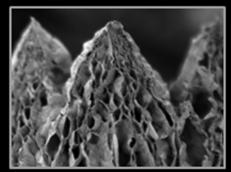
JSM-7800F Prime

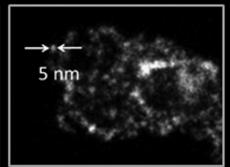


SUB-NANOMETRIC IMAGING

& NANOMETRIC ANALYSIS

Resolution: 0.7nm from 30kV to 1kV





Graphene (80V)

EDS analysis of nanoparticles





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No two vacuum processes are alike since individual requirements are what matters. Together with our customers, we obtain a vacuum solution based on their specific needs. This process includes all steps in creating a perfect vacuum condition. Besides best-in-class products for vacuum generation, measurement and analysis, we also offer accessories, application training programs and worldwide service.

